

# 基于CGH多镜定姿定态的离轴光学系统装调方法

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**摘要** 针对离轴光学系统装调过程中自由度高且互相耦合的问题,提出一种新的离轴自由曲面反射式光学系统装调方法,采用计算全息图(CGH)实现多镜共基准定姿定态,解耦合系统各镜片的装调自由度,显著降低系统装调复杂度;分析 CGH用于定姿定态时的定位精度,提高系统装调精度和效率,适应不同构型的离轴光学系统。利用上述方法,完成口径 为210 mm、视场为2°×2°的近红外长波红外双波段离轴反射式光学系统装调,全视场波像差 RMS 小于 0.126λ(λ= 632.8 nm),达到设计预期,装配周期短,成像质量优良。

1引言

机载光电系统多功能、高性能、轻量化的发展趋势,对光学系统研制提出了更高的要求。反射式光学系统因其宽波段、紧凑化的工作特性被广泛应用到各类机载光电设备中,其中自由曲面离轴三反光学系统能够弥补传统同轴反射系统次镜遮拦、视场小及优化自由度低的缺点。随着自由曲面设计加工技术的发展和成熟,自由曲面面形检测和系统装调成为当前限制自由曲面离轴反射式系统应用的关键<sup>[12]</sup>。

2013年,中国科学院长春光机所王超等[34]利用 双计算全息图(CGH)分别对次镜、三镜定位,研制了 一套三镜消像散系统。以三镜面形检测CGH为基 准开展系统装调,实现了0.16λ(全文若无特殊说明,  $\lambda = 632.8 \, \text{nm}$ ) 全视场波像差 RMS。该方法采用双 CGH进行基准传递,存在误差积累。同年,中国科学 院西安光机所庞志海[5]使用逆向优化法对自由曲面 离轴三反光学系统进行全过程计算机辅助装调,实 现了0.09λ的全视场波像差RMS。但是全过程计算 机辅助逆向优化法的鲁棒性较差,难以支持大误差 系统的研制,且计算过程中会出现非唯一解,导致装 调周期难以控制。2020年,中国科学院长春光机所 李蕾[6]针对自由曲面离轴三反系统的失调量敏感度 矩阵开展研究,建立离轴三反系统失调量求解模型, 使用该模型指导装调能够有效降低系统平均波像 差,经过两轮迭代后平均波像差RMS从0.6 )降低到 0.1 以下。

目前,关于自由曲面离轴反射系统装调方法的研 究聚焦在基准精度提高和计算机辅助装调模型设计, 但离轴系统装调自由度多、复杂度较高,因此上述方法 存在误差的传递难以抑制,导致装调周期长、效果不 佳。本文提出一种基于CGH的多镜定姿定态装调方 法,实现了多镜片装调自由度解耦合,从而控制误差传 递,降低系统装调复杂度。利用该方法可在短周期内 完成一套自由曲面离轴三反系统装调,成像质量中心 的视场波像差 RMS 为0.079λ。

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## 2 装调理论及方法

在以往的研究中,CGH用于单镜面形检测的技术 较为成熟,但对多镜片面形检测区域进行共基准设计, 并将待测面空间位置作为参数参与多镜定姿定态 CGH设计,国内尚未有公开报道。本文提出一种基于 多镜面形检测CGH共基准设计实现装调时各镜面独 立高精度定位的装调方法,其设计思路的核心在于: 1)检测与设计联合,保证系统实现面形高精度检测,同 时实现多镜片高精度定姿定态;2)多自由度解耦,大幅 降低装调复杂度,提升装调效率和精度。

## 2.1 共基准面形检测与定姿定态联合 CGH 设计

与单镜检测CGH不同,为实现多镜共基准定姿定 态装配设计,需要添加镜片离轴量、镜片姿态倾角等额 外参数信息,以满足兼顾镜面CGH检测与实现多镜间 多参数计算机辅助装调、基准传递、镜片定姿定位的设 计要求。CGH设计流程如图1所示。在CGH设计过 程中,为满足共基准设计需求,需反复迭代优化,视情

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况调整CGH设计参数,直至同时满足双镜定姿定态且可加工的CGH设计要求。具体设计过程如下:

1) 输入所设定的待测面参数,包括姿态参数和面 形参数。

2)根据参数计算 CGH 姿态优化初始点。优化 CGH 姿态参数(CGH 倾斜量、CGH 相对待测 面距 离),使主镜、三镜面形检测全息区域完整,且大小适 中,便于检测。

3)根据姿态参数设计其余辅助全息区域,包括粗 对准全息区域、角度对准全息区域、干涉级次标记全息 区域。其中,角度对准全息区域采用反射光栅设计,闪 耀角度为所设计的干涉仪光线入射角度。入射角度由 干涉条纹对比度公式确定,即

$$\gamma = \frac{2\sqrt{C}}{1+C} \left(\gamma > 0.3\right), C = \frac{I_{\text{test}}}{I_{\text{ref}}}, \quad (1)$$

式中:*I*<sub>test</sub>和*I*<sub>ref</sub>分别表示测试光强与参考光强;γ表示 条纹清晰度。调整衍射效率以适配参考光与待测光光 强比约为1:0.04。

4)考察设计条纹的可加工性<sup>[7]</sup>,若条纹满足加工 要求,则认为完成定姿定态CGH设计,可以进行系统 装调;否则返回步骤1),重新调整设计参数直至条纹 满足加工要求。



图 1 CGH设计流程 Fig. 1 CGH design flow

单次 CGH 设计流程中可能出现无法满足加工要 求的情况,因此在设计过程中设置反馈环节,以保证光 学系统的检测性与装配性。在反馈环节中对设计提出 改进要求以适应装调方法,改变曲率半径或调整镜片 间相对姿态。图2显示,光学系统设计优化过程中,元件曲率半径、元件尺寸变化与对应CGH线宽呈线性关系,待测面曲率半径越大,对应CGH条纹越宽,而全部待测面的最小包络圆半径越小,对应CGH条纹越宽。



图 2 CGH条纹线宽变化趋势。(a)镜面曲率半径影响;(b)全镜片包络口径影响 Fig. 2 Trends in stripe linewidth of CGH. (a) Effect of raidus of curvature; (b) effect of envelope aperture

# 2.2 基于多参数计算机辅助装调与CGH共基准传递 装调的方法

离轴系统的单镜片有6个自由度,传统装调方法 中镜片存在耦合,过高的复杂度导致系统装调困难,目 前常用的降低系统装调难度的方法为基准传递方 法<sup>[8-10]</sup>和共基准设计方法<sup>[11]</sup>。本研究采用共基准设计 的CGH实现主镜、三镜的定姿定态,提高装调定位精 度,实现各镜片解耦合,避免误差在传递中扩大,同时 避免系统调节过程陷入局部最优解。装调方法的流程 如图3所示,具体细节如下:

1)根据设计的系统参数完成双镜定姿定态CGH 设计;

2)设置CGH装调基准,以CGH主镜对准区域为装 调基准,调整干涉仪与CGH主镜对准区对准并固定;

3)主镜装调,根据主镜干涉仪对准全息区域调整 干涉仪姿态,姿态定位失调量由该检测光路的灵敏度

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矩阵反映,根据灵敏度矩阵理论,小失调量时Zernike 多项式系数与失调量呈线性关系<sup>[12-15]</sup>,此时根据干涉 条纹Zernike系数精调主镜;

4) 三镜装调,根据三镜干涉仪对准全息区域调整 干涉仪姿态,并根据干涉条纹Zernike系数精调三镜, 完成主镜、三镜定姿定态;

5)建立系统装调基准,以干涉仪为基准,使用经纬 仪对准系统基准和出瞳处准直镜至轴上零视场;

6)次镜装调,使用准直激光定位次镜姿态滚转和 倾斜;

7)精调次镜,使系统零视场成像质量达到设计 要求;

8)调整干涉仪和准直镜到轴外视场的角度,测量 轴外视场成像质量,若满足设计要求,结束系统装调, 否则回到零视场继续调整波像差,直到轴外视场也满 足设计要求。



图 3 装调方法流程图 Fig. 3 Adjustment flow diagram

## 3 仿真设计与误差分析

## 3.1 设计参数

光学系统设计参数如表1所示,自由曲面离轴三 反系统的光路如图4所示。CGH条纹的加工极限为 1.5μm,口径限制单全息区域不超过80mm,完整 CGH口径不超过160mm。

## 3.2 CGH光路布局设计

依据2.2节给出的设计流程完成图5(a)所示的 CGH设计,条纹最小线宽为1.78μm,两个主全息区 域的口径分别为75mm和60mm,完整口径为 150mm,满足制造工艺和设计要求。在光学成像设计 软件CODEV中进行面形检测的仿真,共基准CGH测 试光路如图5(b)所示。

র	長1 系统设计参数	
Table 1	Designed system parameters	
Parameter	Value	
perture of pri	mary	

Light aperture of primary mirror	210 mm
Light aperture of third mirror	120 mm
	Near infrared (NIR) band:
	0.7-0.9 μm;
Operating band	Long wave infrared(LWIR)
	band: 8-12 μm
	NIR band: $0.4^{\circ} \times 0.4^{\circ}$ ;
Field of view (FoV)	LWIR band: $2^{\circ} \times 2^{\circ}$
	Full FoV of NIR RMS:
T	$< 0.10\lambda;$
Imaging quality	Full FoV of LWIR RMS:
	$< 0.23\lambda$

## 3.3 共基准传递CGH误差分析

共基准传递CGH定位精度受设计误差与制备误 差影响。基于系统设计主镜、三镜面形参数和空间 位置参数生成仿真模型,CGH模型使用3.2节的设







计结果,仿真结果为设计的CGH波前与实际待测面 的面形误差。误差表示设计的CGH透射波前与实 际待测面的面形误差,误差仿真结果如图6所示,主 镜检测面形 RMS为0.017λ,三镜检测面形 RMS为 0.016λ。



#### 图5 CGH设计。(a)CGH设计图;(b)共基准CGH测试光路图







Fig. 6 Simulation results of CGH shape detection for primary mirror and third mirror. (a) Result of primary mirror; (b) result of third mirror

制备误差分析可以简化所提模型为线性光栅模型<sup>[12,16-17]</sup>,如图7所示。其中,S为光栅周期,b为蚀刻区域线宽,占空比*D*=*b*/*S*,*A*<sub>0</sub>和*A*<sub>1</sub>分别为未蚀刻区域与蚀刻区域透射波前振幅,在相位型CGH中二者的差可忽略不计,φ为未蚀刻区域与蚀刻区域的相位深度差。



图 7 简化 CGH 光栅模型 Fig. 7 Simplified CGH model

主要制备误差为基底面形误差、条纹线宽误差、蚀 刻深度误差和条纹占空比误差。其中对CGH成像影 响最大的是基底面形误差,但基板的制作精度小于

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λ/100,且不影响后续刻蚀条纹的制备,因此不予关注。 计算得到的其余主要制造误差数值如表2所示。其余 误差在公差范围内引起的波像差变化均小于λ/90,对 CGH定位精度的影响微小。生产制造中应首先抑制 基板面形误差,其次关注条纹线宽误差,以进一步提高 CGH面形检测精度。

表 2 CGH制造中主要误差对波前的影响 Table 2 Influence on wavefront by primary error in CGH

fabrication

Туре	Tolerance	RMS $/\lambda$
Stripe linewidth	0. 2 μm	0.011
Etching depth	1 %	0.005
Duty cycle	1 %	—

## 3.4 CGH定位精度与系统公差分析

对实际加工的CGH成品进行透射波前检测,结果 如图8所示。由图8可知,主镜全息区域0级透射波前 误差为7.8nm,面形检测时带来误差约0.0123λ,而三 镜全息区域0级透射波前误差为6.7nm,面形检测时 带来误差约0.0106λ,符合设计预期,满足定姿定态精 度要求。



图8 CGH透射波前检测结果。(a)主镜全息区域检测结果;(b)三镜全息区域检测结果

Fig. 8 Results of transmitted wavefront of CGH. (a) Result of primary mirror holographic region; (b) result of third mirror holographic region

CGH实测误差数据如表3所示,其中透射波前误 差为平行光入射全息区域的0级透射波前误差,综合 波前误差小于λ/80,达到面形检测精度要求。

通过干涉仪测试结果计算CGH定位精度。实际

表3	实物CGH误差分析	
Table 3	Error of physical CGH	
Туре	Error	RMS $/\lambda$
Primary area RMS	7.8 nm	0.0123
Third area RMS	6.7 nm	0.0106
Duty cycle	0.4%	0.0032

干涉仪测量时 Zernike 系数计算到小数点后两位,根据 Zernike 系数精度 0.01,分别计算得到主镜和三镜的各 参数定位精度如表 4 所示。主镜沿 Y方向的离轴量为 35.0  $\mu$ m,离焦量(Z)为 2.1  $\mu$ m,俯仰角( $\alpha$ )为 13.68", 方位角( $\beta$ )为 10.08",滚转角( $\gamma$ )为 92.16";三镜沿 Y方 向的离轴量为 65.8  $\mu$ m,离焦量为 3.0  $\mu$ m,俯仰角为 12.24",方位角为 26.64",滚转角为 483.80"。

光学系统公差分析首先依据加工装调经验生成一 组公差限,进行蒙特卡罗模拟统计,选择放松或收紧公 差限,最终得到一个合理的公差范围。高斯概率密度

	表4	CGH定位精度	
1 1	4	COLL	

Table 4 CGH locating accuracy						
Mirror	$\alpha$ /(")	$\beta$ /(")	γ /(")	$X \operatorname{decenter} / \mu \mathrm{m}$	$Y$ decenter $/\mu m$	$Z/\mu m$
Primary mirror	13.68	10.08	92.16	26.1	35.0	2.1
Third mirror	12.24	26.64	483.80	51.9	65.8	3.0

函数公差分布以及蒙特卡罗统计1000次的公差分析 结果所给出的公差极限如表5所示,其中补偿量来自 次镜,可满足90%概率下系统中心视场波像差RMS 优于0.08λ。对比CGH定位精度与系统公差范围,各 项参数定位精度均满足系统公差要求,因此认为该定 位精度下装调系统可满足设计要求。

表5 各类公差限范围 Table 5 Value range of various tolerances

Tolerance type	Primary mirror	Third mirror
$X$ decenter $/\mu m$	$\pm 50$	$\pm 100$
$Y$ decenter $/\mu m$	$\pm 50$	$\pm 100$
$Z/\mu m$	$\pm 5$	$\pm 5$
Tilt /(")	$\pm 100$	$\pm 500$

## 基于CGH双镜定姿定态装调方法 4 验证

基于共基准CGH多镜定姿定态的装配光路如

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图 9 所示。首先装调主镜,单镜面形 RMS 为 0. 022λ; 然后装调三镜,单镜面形RMS为0.032λ,达到单镜装 调面形 RMS小于 0.050λ 的设计要求;最后装调次镜, 最终测量中心视场波像差 RMS 为 0.079λ, 如图 10 所示。

### interferometer CGH secondary mirror



图 9 基于共基准 CGH 多镜定 姿定态装配光路图 Fig. 9 Lightpath of optical system attitude determination using CGH



图10 系统中心视场测试结果

Fig. 10 Result of wavefront error measurement of center field of view

全视场成像质量特征点数据如表6所示。视场角 调节通过经纬仪定位,并旋转光学系统实现。从表6 可以看到,近红外光波段全视场波像差RMS小于

0.093λ, 长波红外波段全视场波像差 RMS 小于 0.126λ, 中心视场波像差 RMS 为 0.079λ, 达到设计对 成像质量的要求。

	Table 6 Results of w	avefront error measur	rement of full field of	of view	
Elevation angle $\alpha / (\circ)$		WF	FE RMS of full Fo	V/λ	
	$\beta = -1^{\circ}$	$\beta = -0.2^{\circ}$	$\beta = 0^{\circ}$	$\beta = 0.2^{\circ}$	$\beta = 1^{\circ}$
-1	0.126	—	0.118	_	0.089
-0.2	_	0.083	0.084	0.080	—
0	0.096	0.093	0.079	0.085	0.078
0.2	_	0.087	0.088	0.082	—
1	0.084	—	0.113	—	0.080

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#### 5 结 论

提出一种基于CGH的多镜同步定姿定态装调方 法,实现自由曲面离轴反射式光学系统镜片间的解耦 合,显著降低系统装调难度,缩短装调周期,提高装调 效率和精度。同时给出装调对设计的要求,通过指导 设计迭代提高方法的适用性。基于CGH的定位精度 远高于系统要求的装配公差极限,完成自由曲面离轴 三反系统装配,近红外光波段全视场波像差RMS小于 0.093\, 长波红外波段全视场波像差 RMS 小于 0.126λ,中心视场波像差 RMS 为 0.079λ。该方法具 有良好的应用前景,将该方法应用于分离式结构装调,

在主镜三镜一体化结构中也有较高的应用价值,利用 CGH高精度定位可以实现共基底加工误差的校准。 该方法可广泛应用于自由曲面离轴系统装调、含自由 曲面光学系统设计等领域。

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## Alignment Method for Off-Axis Optical Systems Based on CGH Multi-Mirror Attitude Determination

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## Abstract

**Objective** The development trend of onboard electro-optical systems towards multifunctionality, high performance, and light weight poses higher demands on the development of optical systems. Reflective optical systems are widely employed in various types of onboard electro-optical devices due to their broad bandwidth and compact working characteristics, and they face challenges such as obscuration of secondary mirrors, limited field of view, and low optimization degrees in traditional coaxial reflective systems. Off-axis three-mirror reflective optical systems with freeform surfaces can address these issues. However, the development and maturity of freeform surface design and manufacturing techniques pose challenges to freeform surface shape measurement and system alignment. In previous studies, computer-generated holograms (CGHs) are adopted for single mirror shape measurement, but there is limited publicly available information on multi-mirror shape measurement with CGHs and their joint baseline design.

Methods We propose a method for CGH joint baseline design of multi-mirror shape measurement to enable independent high-precision positioning of each mirror during alignment. The core idea is to combine detection and design to ensure highprecision shape measurement and achieve high-precision positioning and stabilization of multiple mirrors. The specific process of the joint baseline design for multi-mirror CGHs is as follows (Fig. 1). 1) The input parameters for the mirror shape are set, including posture parameters and surface parameters. 2) The initial point for CGH posture optimization is calculated based on the parameters. Additionally, CGH posture parameters (tilt and distance from the measured surface) are optimized to ensure the integrity and moderate size of the holographic areas for primary mirror and third mirror. 3) Additional holographic areas are designed based on posture parameters, including rough alignment areas, angular alignment areas, and interference order marking areas. The angular alignment area utilizes a reflective grating design with the shining angle set as the incident angle of the interferometer's light rays. 4) The manufacturability of the designed fringe patterns is examined. If the patterns meet the processing requirements, the joint baseline design is considered complete to proceed to system alignment. Otherwise, the first step should be returned and the design parameters should be readjusted until the fringe patterns meet the processing requirements. The alignment process using multi-mirror joint baseline design CGH is as follows (Fig. 3). 1) The two-mirror posture optimization CGH design is finished based on the system parameters. 2) The CGH alignment baseline is set, the interferometer is aligned with the main mirror alignment area, and the alignment of the interferometer and the main mirror is fixed. 3) The primary mirror is aligned. The interferometer posture is adjusted based on the alignment area of the main mirror interferometer. The misalignment is reflected by the sensitivity matrix of the detection optical path. According to the sensitivity matrix theory, under small misalignment, Zernike polynomial coefficients are linearly related to the misalignment. The main mirror should be fine-tuned based on interferometric fringe Zernike coefficients. 4) The third mirror is aligned. The interferometer posture is adjusted based on the alignment area of the three-mirror interferometer and the third mirror are fine-tuned based on the interferometric fringe Zernike coefficients. Meanwhile, the posture and stabilization of primary mirror and third mirror are completed. 5) The system alignment baseline is established by the interferometer, and a theodolite is employed to align the system baseline and the reticle at the exit pupil. 6) The secondary mirror is aligned. A collimated laser is adopted to position the tilt and pitch of the secondary mirror. 7) The secondary mirror is fine-tuned to achieve the desired image quality at the zero field of view. 8) The angles of the interferometer and the collimated mirror are adjusted to the off-axis field of view, and the imaging quality at the off-axis field of view is measured. If it meets the design requirements, system alignment is ended. Otherwise, the zero field of view should be returned and the wavefront error adjustment should be continued until the offaxis field of view also meets the design requirements.

**Results and Discussions** The CGH design is limited by the following factors, including minimum stripe width greater than  $1.5 \,\mu\text{m}$ , single holographic area diameter smaller than  $80 \,\text{mm}$ , and complete CGH diameter smaller than  $160 \,\text{mm}$ . The designed CGH (Fig. 5) with minimum stripe width  $1.78 \,\mu\text{m}$  meets the manufacturing process and design

requirements. The fabrication error analysis can simplify the model to a linear grating model (Fig. 7). The main fabrication errors (Table 2) contain substrate shape error, stripe width error, etching depth error, and stripe duty cycle error. Among them, the substrate shape error has the most significant influence on CGH imaging. However, the substrate's manufacturing accuracy is smaller than  $\lambda/100$  and does not affect subsequent preparation of etched stripes. The other errors cause wavefront error changes within the tolerance range and have a minimal effect on CGH positioning accuracy. In production, it is essential to first suppress substrate shape errors and then pay attention to stripe width errors, further improving the precision of CGH shape measurement. Transmission wavefront measurement (Fig. 8) is performed on the fabricated CGH product. The comprehensive wavefront error in the measured CGH is less than  $\lambda/80$ , which meets the requirements for shape measurement accuracy. In the experiment (Table 3), the main mirror is aligned first, and the RMS of the single mirror shape is 0. 022 $\lambda$ . Then, the three mirrors are aligned and the RMS of the single mirror shape is 0. 032 $\lambda$ , which satisfies the design requirement that the RMS of the single mirror alignment shape should be less than 0. 050 $\lambda$ . Finally, the secondary mirror is aligned. In the full-field imaging quality test (Table 6), the field angle adjustment is realized via theodolite positioning and optical system rotation. The RMS wavefront aberration in the near-infrared wavelength range is less than 0. 093 $\lambda$ , and in the long-wave infrared wavelength range, it is less than 0. 126 $\lambda$ . The RMS wavefront aberration at the central field of view is 0. 079 $\lambda$ , which meets the design requirements for imaging quality.

**Conclusions** This method has excellent application prospects. Meanwhile, it is applied to separate structure alignment in this study and has application significance in the off-axis three-mirror integrated structures. High-precision positioning using CGH can calibrate the common baseline machining errors. This method can be widely adopted in the alignment of freeform off-axis systems and the design of optical systems with freeform surfaces.

Key words optical design; computer-generated hologram; off-axis three-mirror; freeform surface